


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517214	<b>Applicant(s)/Patent Under Reexamination</b>  MAEKAWA ET AL.
	<b>Examiner</b>  Jaisle, Cecilia M	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
514	403, 404	10/10/2007	Cecilia Jaisle
548	373.1, 375.1	10/10/2007	Cecilia Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner